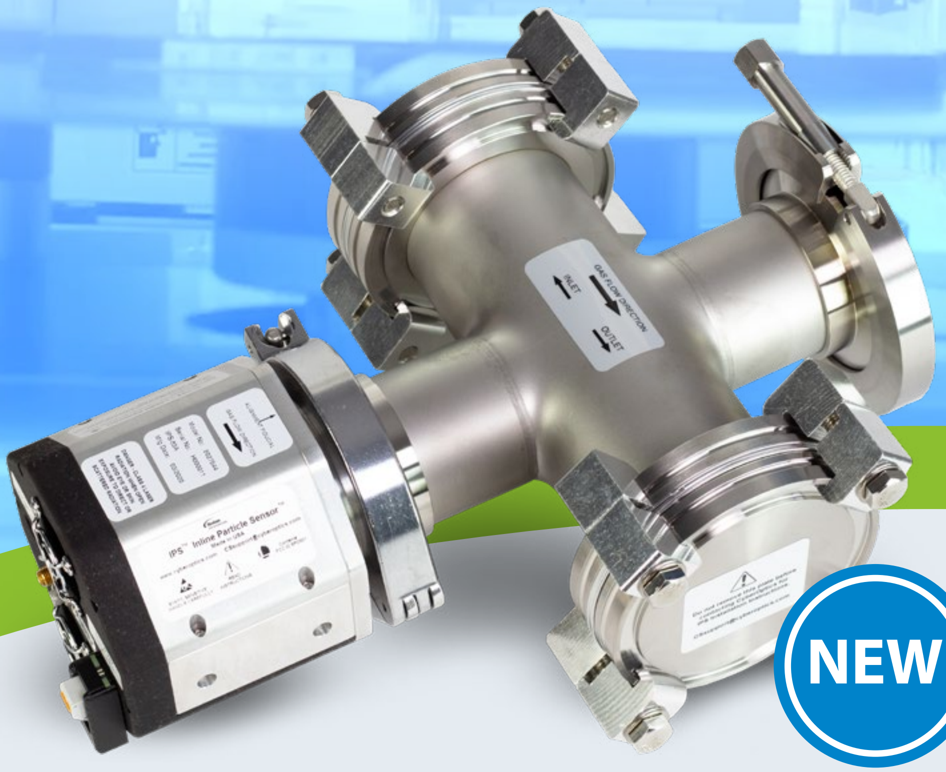
Save Time **Save Expense** **Improve Yields**

Semiconductor fabs and OEMs worldwide value the accuracy, precision and versatility of Nordson TEST & INSPECTION's semiconductor measurement devices. The most efficient and effective measurement devices for tool optimization, stabilization and standardization.



WS

NEW

WaferSense®

In-Line Particle Sensor™ (IPS)

24/7 detection

Of small particles in gas and vacuum lines.

Based on our WaferSense® Airborne Particle Sensor™ technology, IPS utilizes a high power blue laser to quickly monitor, identify and enable troubleshooting of particles down to 0.1µm within gas and vacuum line locations for process sensitive applications.

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Nordson
TEST & INSPECTION

WaferSense® In-Line Particle Sensor™ (IPS)

Speed Equipment Qualification

With real-time 24/7 monitoring.

- Collect and display particle data using IPS and the new CyberSpectrum™ software for real-time equipment diagnostics.
- Compare past and present data as well as one tool to another easier and faster with CyberSpectrum.
- Save time by swiftly locating contamination sources. See the effect of cleanings, adjustments and repairs in real time.

Shorten Maintenance Cycles

Shorten equipment maintenance cycles with inline particle sensing.

- Detect particles in real-time and correlate measurements with tool events.
- Develop a baseline performance for tool and process.
- Simplify maintenance cycles by selectively servicing portions of a tool causing particle generation.

Lower Equipment Expenses

With objective and reproducible data.

- Reduce the need, cost and complexity of particle adder testing that requires usage of test wafers and masks.
- Receive early warning for impending equipment failures and optimize your preventative maintenance plans.

Multiple Line Locations

Install IPS in multiple line locations for a variety of applications.

- Versatile particle sensing for any application that is process sensitive to particles including semiconductor processing equipment, EUV chambers, vacuum chambers, 3D metal printing equipment, equipment in controlled environments and more.

For more information, speak with your Nordson representative or contact your Nordson regional office

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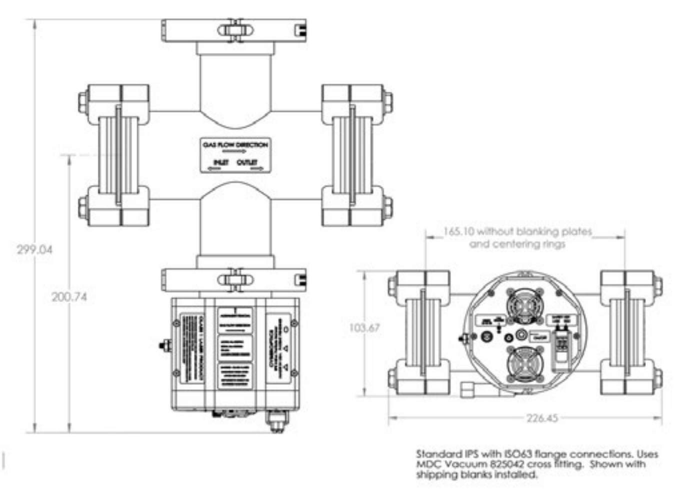
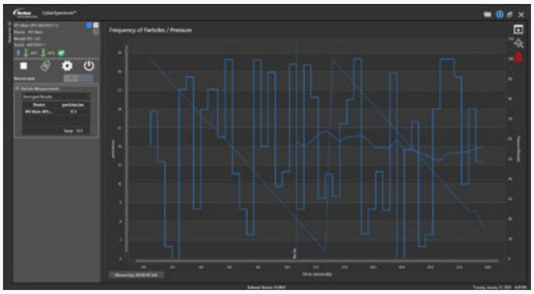
Specifications	
Mechanical interface	ISO-63 flange (standard configuration)
Software	CyberSpectrum
Accuracy	Measures particles greater than 0.1µm Less than 5 false counts per hour
Vacuum exposed materials	Aluminum, Glass, Viton O-Rings, Stainless steel hardware
Vacuum integrity	Less than 10-6 atm-l/sec leak rate
Operating pressure	PN: 8027544: < 10^{-6} to 250 Torr PN: 8029580: < 10^{-6} to 1520 Torr
Operating temperature	15 °C to 45 °C
Operating humidity	20-90% RH, non-condensing
Laser	Certified to Laser Class 1
Input voltage	12 VDC
IPS Link	Bluetooth, Class 1, 2.4GHz
Operating system	Windows 10
Product components	Sensor head, stainless cross fitting, clamps, power supply, Bluetooth communications link module

Ships with blank flanges on vacuum ports.
Consult factory for installation instructions.

Dimensions



Standard IPS with ISO63 flange connections. Uses MDC Vacuum 825042 cross fitting. Shown with shipping blanks installed.



Real-time data.

CyberSpectrum™ Software

Displays real-time numeric and visual feedback, cumulative or differential counting modes and particle frequency.

Review functionality integrated; replays log file data for review and analysis.

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